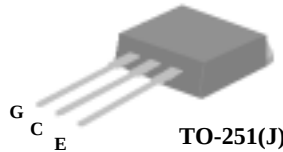
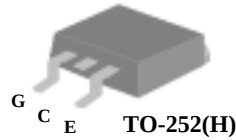


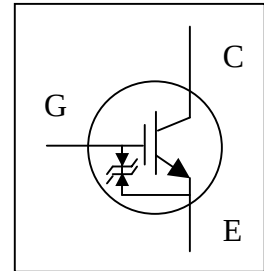


Description

- * High Input Impedance
- * High Pick Current Capability
- * 4.5V Gate Drive
- * Strobe Flash Applications



V_{CES}	450V
I_{CP}	130A



Absolute Maximum Ratings

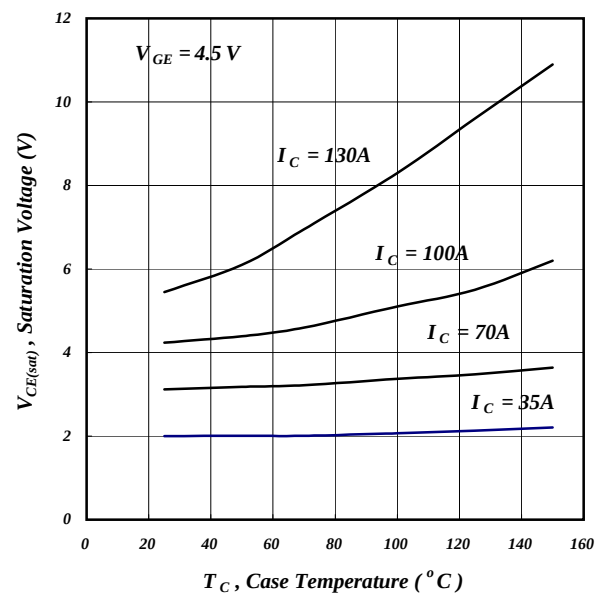
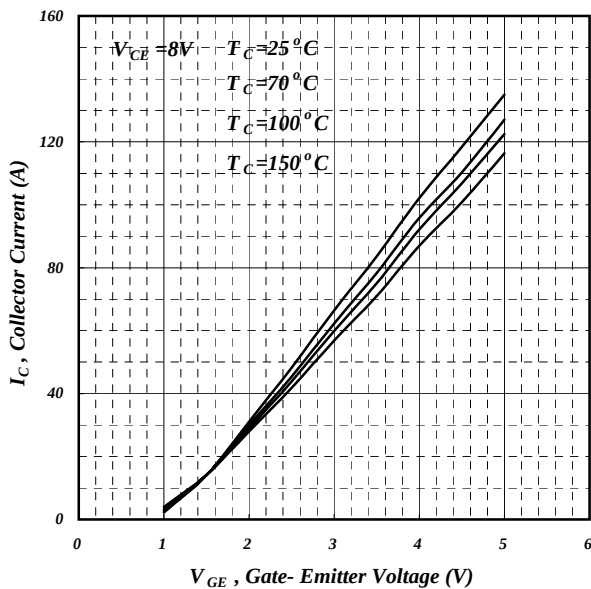
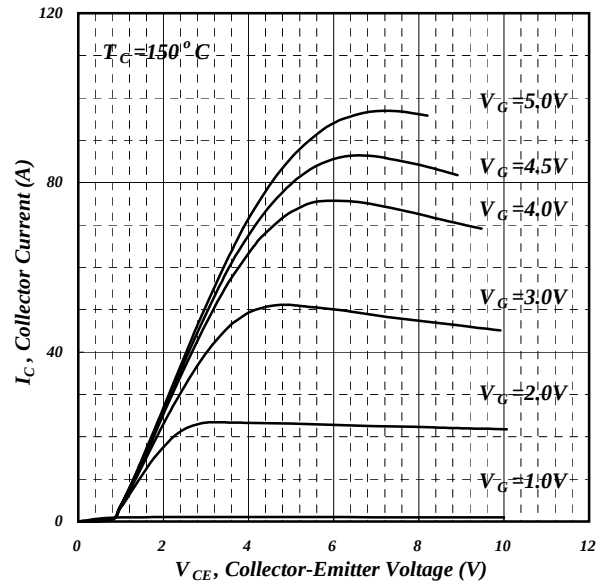
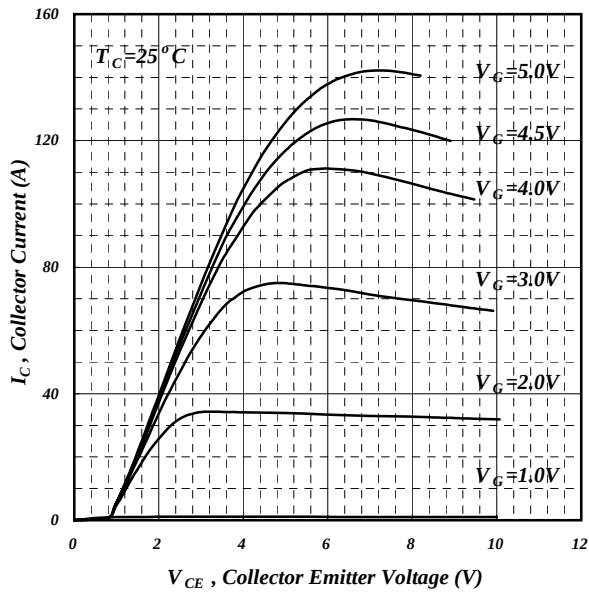
Symbol	Parameter	Rating	Units
V_{CES}	Collector-Emitter Voltage	450	V
V_{GE}	Gate-Emitter Voltage	± 6	V
I_{GEP}	Pulsed Gate-Emitter Voltage	± 8	V
I_{CP}	Pulsed Collector Current	130	A
$P_D @ T_C = 25^\circ\text{C}$	Maximum Power Dissipation	20	W
T_{STG}	Storage Temperature Range	-55 to 150	$^\circ\text{C}$
T_J	Operating Junction Temperature Range	-55 to 150	$^\circ\text{C}$

Electrical Characteristics@ $T_J=25^\circ\text{C}$ (unless otherwise specified)

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Units
I_{GES}	Gate-Emitter Leakage Current	$V_{GE}=6\text{V}, V_{CE}=0\text{V}$	-	-	10	μA
I_{CES}	Collector-Emitter Leakage Current ($T_J=25^\circ\text{C}$)	$V_{CE}=450\text{V}, V_{GE}=0\text{V}$	-	-	10	μA
$V_{CE(sat)}$	Collector-Emitter Saturation Voltage	$V_{GE}=4.5\text{V}, I_{CP}=130\text{A}$ (Pulsed)	-	5	8	V
$V_{GE(th)}$	Gate Threshold Voltage	$V_{CE}=V_{GE}, I_C=250\mu\text{A}$	-	-	1.2	V
Q_g	Total Gate Charge	$I_C=40\text{A}$	-	51	-	nC
Q_{ge}	Gate-Emitter Charge	$V_{CE}=300\text{V}$	-	2	-	nC
Q_{gc}	Gate-Collector Charge	$V_{GE}=5\text{V}$	-	5.4	-	nC
$t_{d(on)}$	Turn-on Delay Time	$V_{CC}=200\text{V}$	-	5.5	-	ns
t_r	Rise Time	$I_C=40\text{A}$	-	72	-	ns
$t_{d(off)}$	Turn-off Delay Time	$R_G=25\Omega$	-	640	-	ns
t_f	Fall Time	$V_{GE}=5\text{V}$	-	2.6	-	μs
C_{ies}	Input Capacitance	$V_{GE}=0\text{V}$	-	2095	-	pF
C_{oes}	Output Capacitance	$V_{CE}=25\text{V}$	-	145	-	pF
C_{res}	Reverse Transfer Capacitance	$f=1.0\text{MHz}$	-	35	-	pF
R_{thj-c}	Thermal Resistance Junction-Case		-	-	6	$^\circ\text{C/W}$



AP20G45EH/J



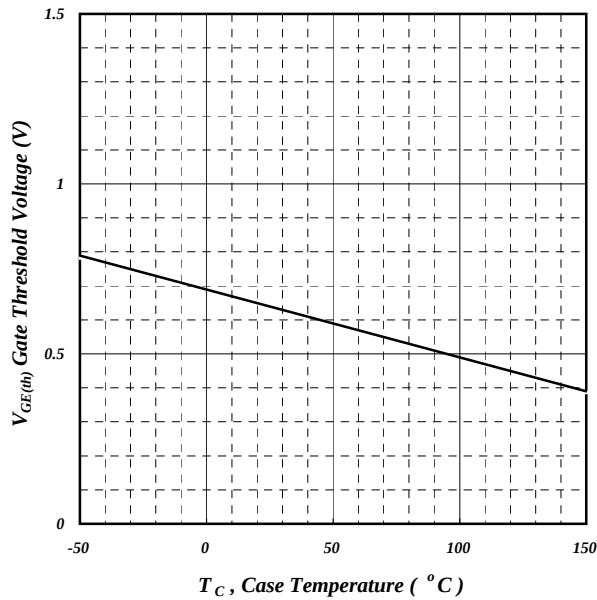


Fig 5. Gate-Emitter Cut-Off Voltage
v.s. Case Temperature

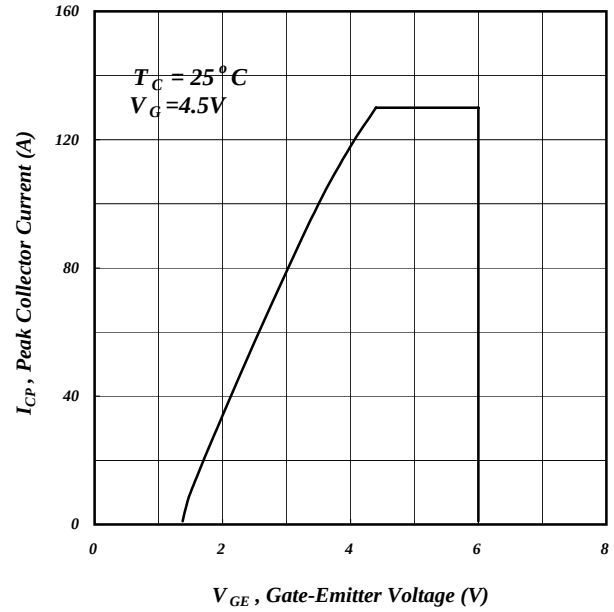


Fig 6. Safe Operation Area

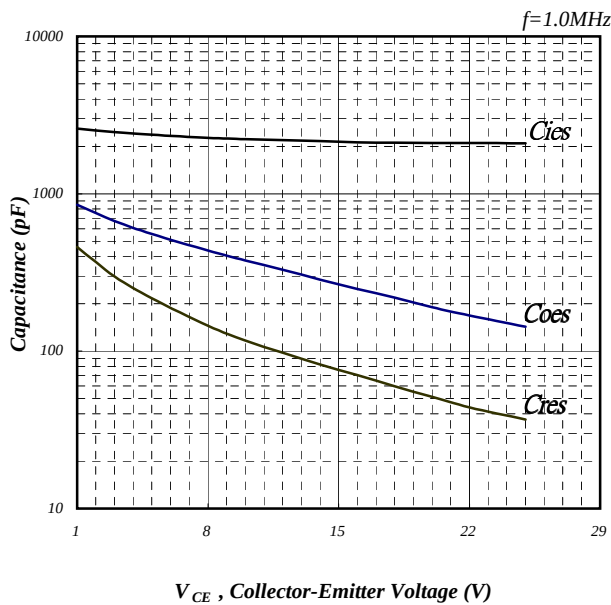


Fig 7. Collector v.s. Collector-Emitter Voltage

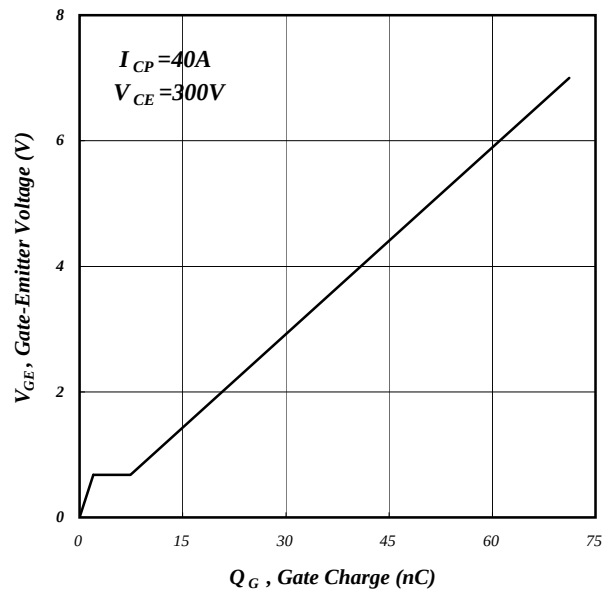


Fig 8. Gate Charge Waveform

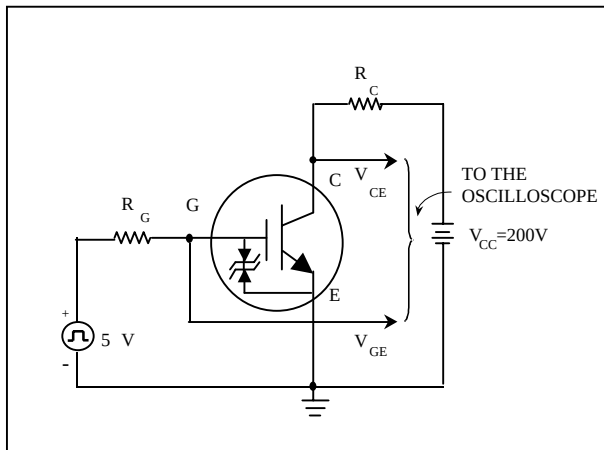


Fig 9. Switching Time Test Circuit

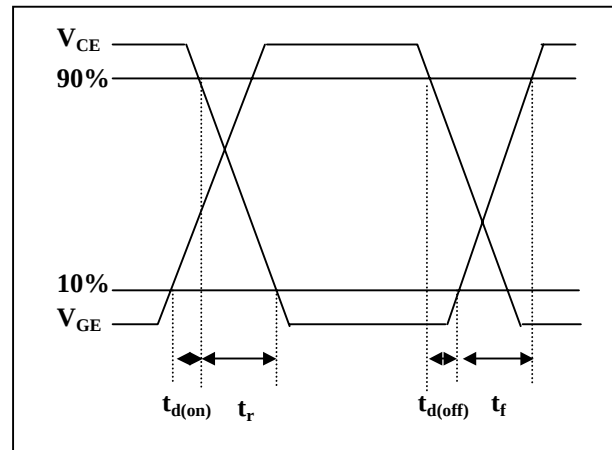


Fig 10. Switching Time Waveform

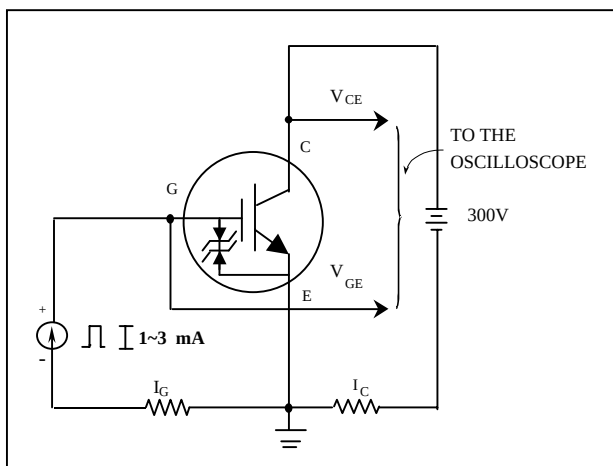


Fig 11. Gate Charge Test Circuit

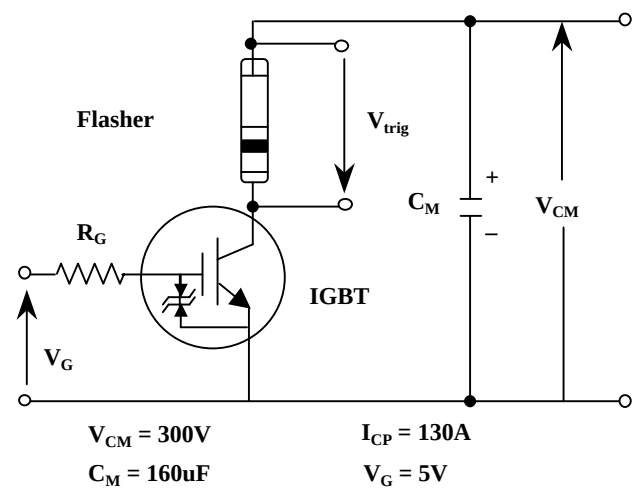


Fig 12. Application Test Circuit